

# CBCS SCHEME



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15EC63

## Sixth Semester B.E. Degree Examination, June/July 2019 VLSI Design

Time: 3 hrs.

Max. Marks: 80

Note: Answer any FIVE full questions, choosing ONE full question from each module.

### Module-1

- Derive the CMOS inverter DC characteristics graphically from p device and n device characteristics and show all operating regions. (08 Marks)
  - Explain the working of nMOS enhancement mode transistor with suitable diagrams. (08 Marks)

OR

- Derive expression for drain current in linear and saturation region for nMOS transistor. (08 Marks)
  - With neat sketches explain the CMOS P-well process steps to fabricate a CMOS inverter. (08 Marks)

### Module-2

- Write the lambda based design rules for separation of layers and transistors. (06 Marks)
  - Draw circuit, stick and layout diagram for nMOS shift register cell. (10 Marks)

OR

- Define sheet resistance ( $R_s$ ) standard unit of capacitance ( $\square C_g$ ) and delay unit ( $\tau$ ) (06 Marks)
  - Calculate the capacitance of the structure given below in Fig.Q4(b). (10 Marks)

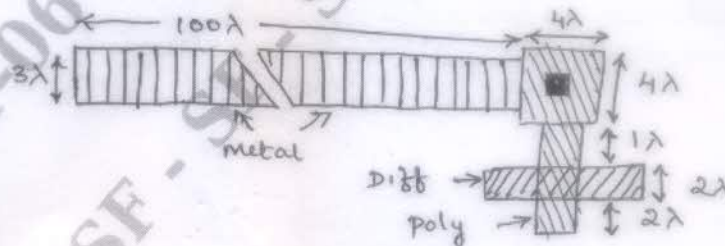


Fig.Q4(b)

- Area capacitance value for metal 1 to substrate =  $0.3\text{pF} \times 10^{-4}/\mu\text{m}^2$  (0.075 relative value)  
 Area capacitance value for diffusion to substrate =  $1\text{pf} \times 10^{-4}/\mu\text{m}^2$  (0.25 relative value)  
 Area capacitance value for polysilicon to substrate =  $0.4\text{ pF} \times 10^{-4}/\mu\text{m}^2$  (0.1 relative value).

Important Note : 1. On completing your answers, compulsorily draw diagonal cross lines on the remaining blank pages.  
2. Any revealing of identification, appeal to evaluator and /or equations written eg, 42+8 = 50, will be treated as malpractice.

**Module-3**

- 5 a. Obtain the scaling factor for the following device parameters :
- i) gate capacitance
  - ii) gate area
  - iii) saturation current ( $I_{dss}$ )
  - iv) channel resistance ( $R_{on}$ )
  - v) maximum operating frequency ( $f_0$ )
  - vi) power dissipation per gate ( $P_g$ )
  - vii) current density ( $J$ )
  - viii) gate delay ( $T_d$ ).
- b. With a neat diagram explain  $4 \times 4$  Barrel shifter.

(08 Marks)

(08 Marks)

OR

- 6 a. Explain the general arrangement of a 4 bit data path for processor. (08 marks)
- b. Describe Manchester carry chain element. (08 Marks)

**Module-4**

- 7 a. Discuss the architectural issues to be followed in the design of VLSI sub system. (05 Marks)
- b. Explain in detail the general structure of an FPGA fabric. (06 Marks)
- c. Explain switch logic implementation of CMOS 5 way selector with neat circuit diagram. (05 Marks)

OR

- 8 a. Explain the structured design approach for the implementation of a parity generator. (08 marks)
- b. Explain dynamic CMOS logic with example. (08 Marks)

**Module-5**

- 9 a. Explain 3 transistor dynamic RAM cell with schematic diagram. (06 Marks)
- b. Explain any two fault models in combinational circuits. (06 Marks)
- c. Write a note on automatic test pattern generation. (04 Marks)

OR

- 10 a. write short notes on :
- i) observability and controllability
  - ii) Built In Self Test (BIST).
- b. Explain nMOS pseudo static RAM cell with schematic diagram.

(08 Marks)

(08 Marks)

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